	Type	# 	Type L # Hits	Search Text	DBs	Time Stamp
	BRS	17	7575	7575 (determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near4 (reflectivit\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/2 8 08:04
~_	BRS	L2	20081	20081 (determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near6 (disc or disk or medium)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/2 8 08:04
m	BRS	L3	23627	((laser or light or beam) near5 (chang\$5 or 23627alter\$5 or modif\$6)) near5 (characteristic or behavior or material or shape)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/2 8 08:09
4	BRS	L4	122	122	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/2 8 08:10
Ŋ	BRS	L6	90259	(first near2 (laser or light or led or beam)) 90259and (second near2 (laser or light or led or beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/2 8 08:11
(o	BRS	L7	54	4 and 6	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/2 8 08:16

	Type	Hits	Search Text	DBs
H	BRS	101088	(determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near8 (disc or disk)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	116822	(first near3 (laser or light or beam)) and (second near3 (laser or light or beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
m	BRS	7440	((laser or light or beam) near5 (chang\$5 or alter\$5 or modif\$6 or correct\$5)) with (reflect\$5 near6 surface)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	290	((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near8 (disc or disk) and (first near3 (laser or light or beam)) and (second near3 (laser or light or beam)) and ((laser or light or beam) near5 (chang\$5 or alter\$5 or modif\$6 or correct\$5)) with (reflect\$5 near6 surface)) and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
5	BRS	178581	optic\$3 near3 (storage or disc or disk)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
ω	BRS	234	(((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near8 (disc or disk)) and ((first near3 (laser or light or beam)) and (second near3 (laser or light or beam))) and (((laser or light or beam) near5 (chang\$5 or alter\$5 or modif\$6 or correct\$5)) with (reflect\$5 near6 surface)) and @ad<=19990320) and (optic\$3 near3 (storage or disc or disk))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	46065	(determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near9 (surface near7 reflect\$6)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
ω	BRS	183	(((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near8 (disc or disk) and (first near3 (laser or light or beam)) and (second near3 (laser or light or beam)) and ((laser or light or beam) near5 (chang\$5 or alter\$5 or modif\$6 or correct\$5)) with (reflect\$5 near6 surface)) and @ad<=19990320) and (determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near9 (surface near7 reflect\$6))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Type	Hits	Search Text	DBs
o	BRS	1591	(determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near6 (surface near4 reflectivity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10	BRS	16	((((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near8 (disc or disk) and ((first near3 (laser or light or beam)) and (second near3 (laser or light or beam)) and ((laser or light or beam) near5 (chang\$5 or alter\$5 or modif\$6 or correct\$5)) with (reflect\$5 near6 surface)) and @ad<=19990320) and ((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near9 (surface near7 reflect\$6))) and ((determin\$5 or detect\$5 or measur\$5 o	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
11	BRS	5529	(laser or light or beam) near9 ((chang\$5 or alter\$5 or modif\$6) near7 ((reflect\$5 or characteristic\$2 or behavior) near4 surface))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
12	BRS	41	((first near3 (laser or light or beam)) and (second near3 (laser or light or beam))) and ((laser or light or beam) near9 ((chang\$5 or alter\$5 or modif\$6) near7 ((reflect\$5 or characteristic\$2 or behavior) near4 surface))) and ((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or examin\$5) near6 (surface near4 reflectivity)) and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Type	#	Hits	Search Text	DBs
	BRS	디디	(1 13573 or or	(light or laser or led) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 (die or area or region))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
2	BRS	L2	5205	(determin\$5 or detect\$5 or analyz\$5 or inspect\$5 or examin\$5) near5 (reflectivit\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
m	BRS	L3	163	1 and 2 and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
4	BRS	L4	803	(determin\$5 or detect\$5 or analyz\$5 or inspect\$5 or examin\$5) near5 (reflectivit\$3 near3 surface)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
5	BRS	1.5	21	1 and 4 and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
9	BRS	Г6	59	((((light or laser or led) near3 (source or beam or diode)) with ((perturb\$5 or disturb\$5 or modif\$7 or chang\$5 or alter\$5) near5 (die or area or region))) and ((determin\$5 or detect\$5 or analyz\$5 or inspect\$5) near5 semiconductor) and @ad<=20000419) not (semiconductor adj laser)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	L7	58	6 not 5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
ω	BRS	L8	10596	(light or laser or led) near5 ((perturb\$5 or 10596disturb\$5 or modif\$7 or chang\$5 or alter\$5) near6 (die or area or region))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
_ ნ	BRS	L9	6215	1 and 8 and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10	BRS	L10	112	8 and 2 and @ad<=19990320	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB